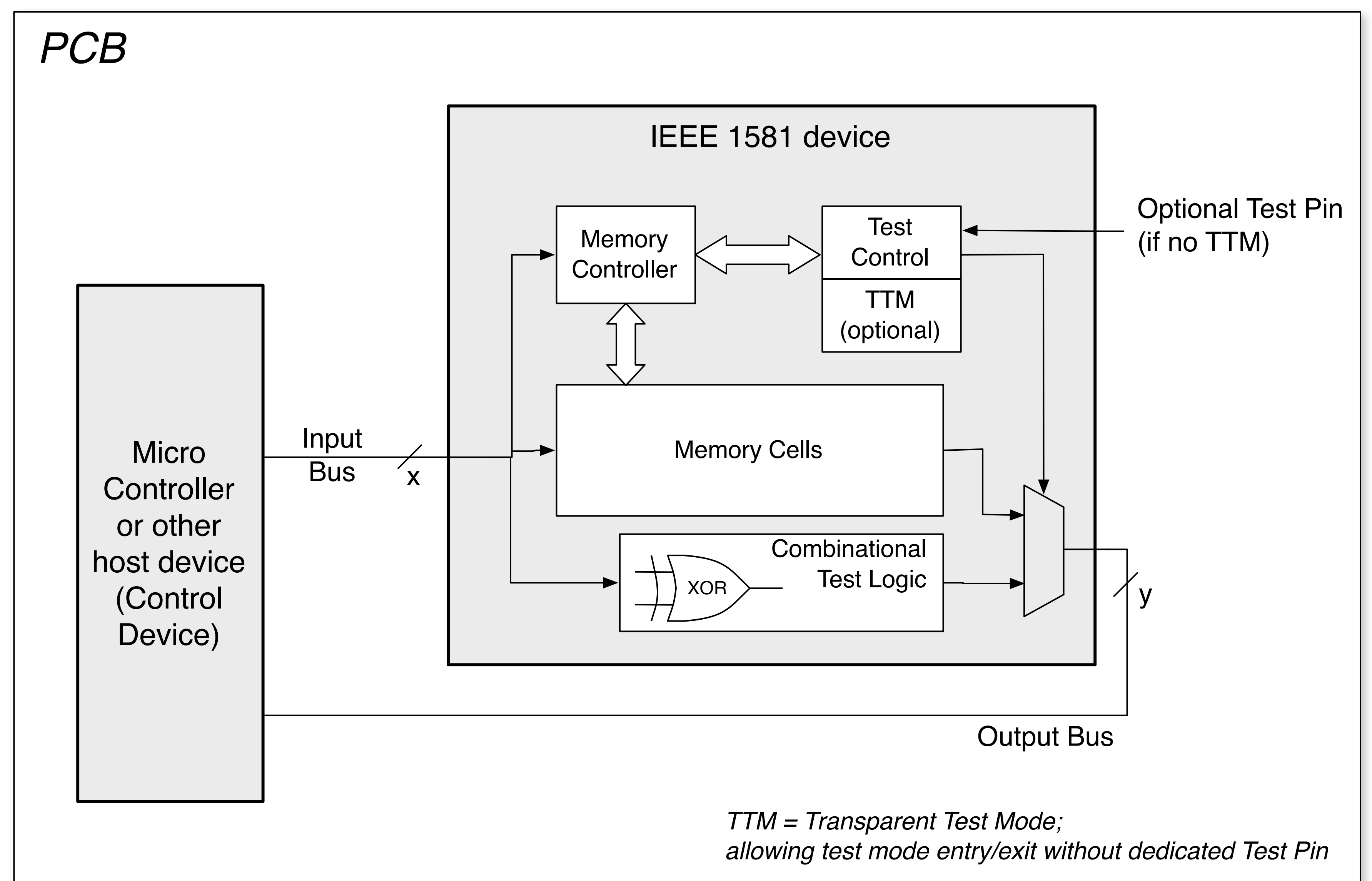


IEEE P1581 drastically simplifies connectivity test for memory devices potentially without any extra pins

IEEE P1581 ...

- requires **no extra pins**;
- uses **simple (inexpensive) test logic** for memory devices and other complex, slave-type components;
- tests **dynamic devices** with **static stimulus** thus avoiding complex memory access cycles, and **preserves non-volatile content**;
- allows **very fast** tests with a **small** test vector set (important for embedded test applications); and
- is usable with **any access methodology** (ICT, functional, and especially – Boundary Scan);

Further Info: <http://grouper.ieee.org/groups/1581/>



Menu of Proposed Test Mode Entry and Exit Methods

